

P-Channel 30V(D-S) MOSFET

Product summary		
V_{DS}	-30	V
$R_{DS(ON)}$ (at $V_{GS}=-10V$) Typ.	55	$m\Omega$
$R_{DS(ON)}$ (at $V_{GS}=-4.5V$) Typ.	67	$m\Omega$
$I_D(TA=25^\circ C)$	-3.5	A

Features

- Trench Power LV MOSFET technology
- High Speed switching
- High density cell design for Low $R_{DS(ON)}$

Applications

- Power management
- Load switch

Pin Configuration



Packing Information

Device	Package	Reel Size	Quantity(Min. Package)
ECDA3403	SOT-23	7"	3000pcs

Absolute Maximum Ratings (at $T_A=25^\circ C$ Unless Otherwise Noted)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	-30	V
V_{GS}	Gate-Source Voltage	± 12	V
I_D	Continuous Drain Current at $V_{GS}=-10V$	$T_A=25^\circ C$	A
		$T_A=70^\circ C$	A
I_{DM}	Pulse Drain Current Tested ^A	-16	A
P_D	Power Dissipation	$T_A=25^\circ C$	W
T_J, T_{STG}	Junction and Storage Temperature Range	-55 to +150	°C

Thermal Characteristics

Symbol	Parameter	Typical	Units
$R_{\theta JA}$	Thermal Resistance-Junction to ambient ^B	104	°C/W

Electrical Characteristics (at $T_J = 25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
Static Parameters						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=-250\mu\text{A}$	-30	--	--	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}}=-30\text{V}, V_{\text{GS}}=0\text{V}$	--	--	-1	μA
I_{GSS}	Gate-Body Leakage Current	$V_{\text{DS}}=0\text{V}, V_{\text{GS}}=\pm 12\text{V}$	--	--	± 100	nA
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=-250\mu\text{A}$	-0.5	-0.95	-1.5	V
$R_{\text{DS}(\text{ON})}$	Drain-Source On-State Resistance ^C	$V_{\text{GS}}=-10\text{V}, I_{\text{D}}=-4.4\text{A}$	--	55	71	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V}, I_{\text{D}}=-4\text{A}$	--	67	87	$\text{m}\Omega$
		$V_{\text{GS}}=-2.5\text{V}, I_{\text{D}}=-2\text{A}$	--	105	131	$\text{m}\Omega$
V_{SD}	Forward Voltage	$I_{\text{S}}=-3.5\text{A}, V_{\text{GS}}=0\text{V}$	--	--	-1.2	V
I_{S}	Maximum Body-Diode Continuous Current		--	--	-3.5	A
Dynamic Parameters ^D						
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=-15\text{V}$ $f=1\text{MHz}$	--	360	--	pF
C_{oss}	Output Capacitance		--	39	--	pF
C_{rss}	Reverse Transfer Capacitance		--	33	--	pF
Q_{g}	Total Gate Charge	$V_{\text{DS}}=-15\text{V}, I_{\text{D}}=-3\text{A}$ $V_{\text{GS}}=0 \text{ to } -10\text{V}$	--	6.5	--	nC
Q_{gs}	Gate-Source Charge		--	1.4	--	nC
Q_{gd}	Gate-Drain Charge		--	1.7	--	nC
$t_{\text{D}(\text{on})}$	Turn-on Delay Time	$V_{\text{DD}}=-15\text{V}$ $, I_{\text{D}}=-3\text{A},$ $R_{\text{GEN}}=3\Omega,$ $V_{\text{GS}}=-4.5\text{V}$	--	10	--	nS
t_{r}	Turn-on Rise Time		--	86	--	nS
$t_{\text{D}(\text{off})}$	Turn-off Delay Time		--	150	--	nS
t_{f}	Turn-off Fall Time		--	357	--	nS
t_{rr}	Reverse recovery time	$I_{\text{F}}=-3\text{A},$ $di/dt=100 \text{ A}/\mu\text{s}$	--	35	--	ns
Q_{rr}	Reverse recovery charge		--	5	--	nC

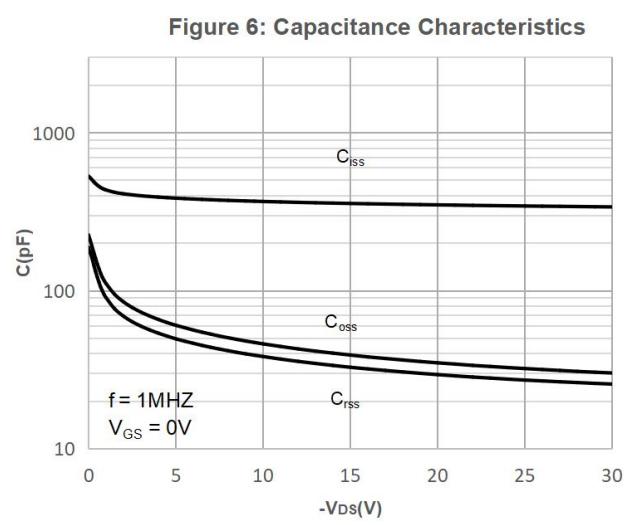
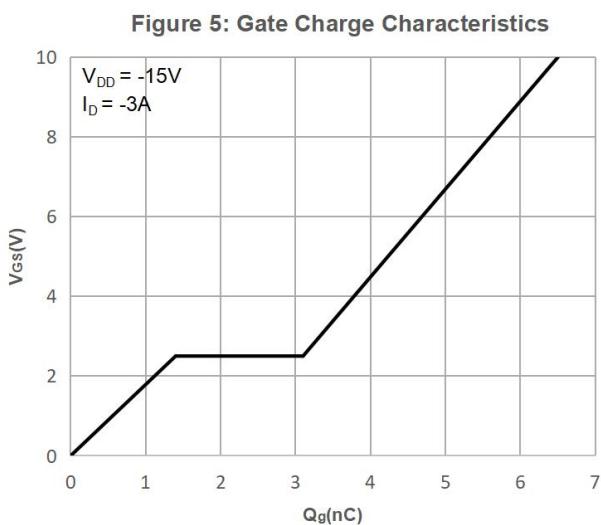
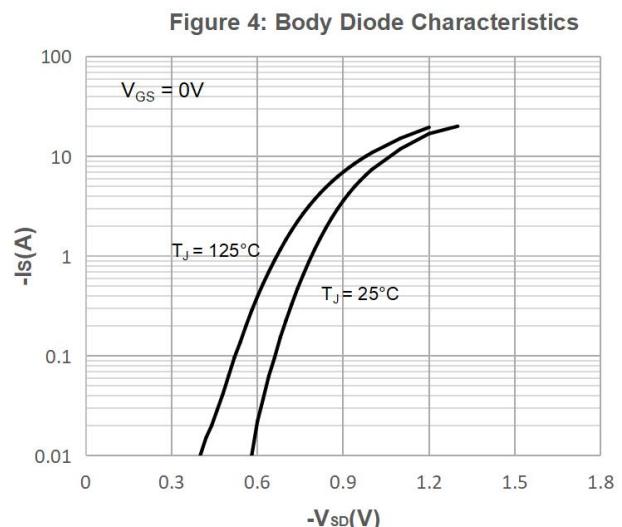
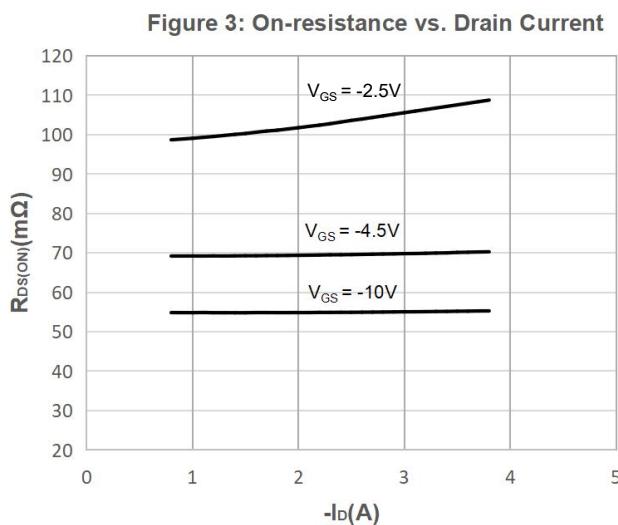
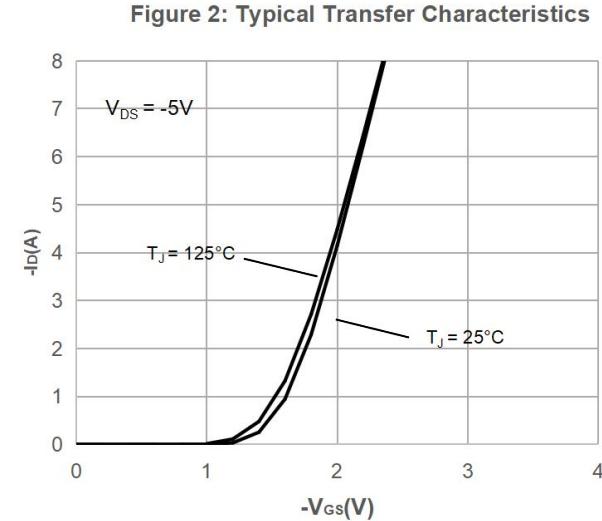
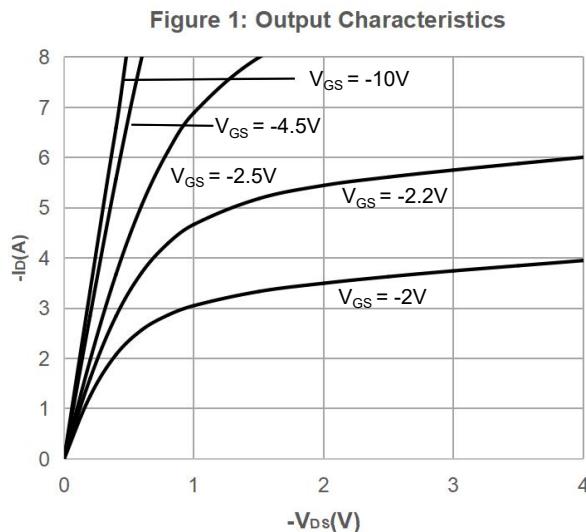
A. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.

B. Device mounted on FR-4 PCB, 1 inch x 1 inch x 0.062 inch.

C. Pulse Test: Pulse Width $\leq 300\text{us}$, Duty cycle $\leq 0.5\%$.

D. Guaranteed by design, not subject to production testing.

Typical Characteristics



Typical Characteristics

Figure 7: Normalized Breakdown voltage vs. Junction Temperature

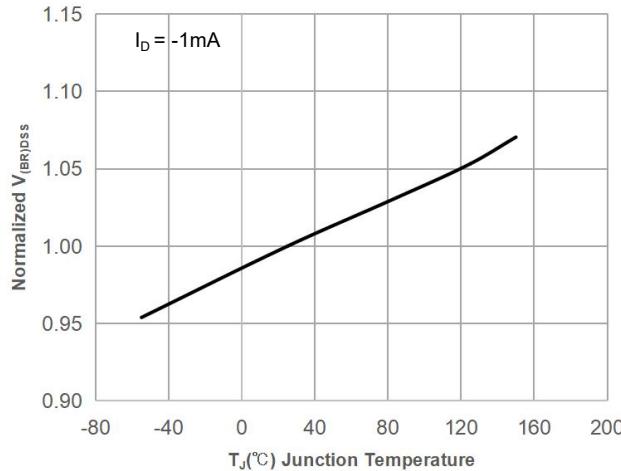


Figure 8: Normalized on Resistance vs. Junction Temperature

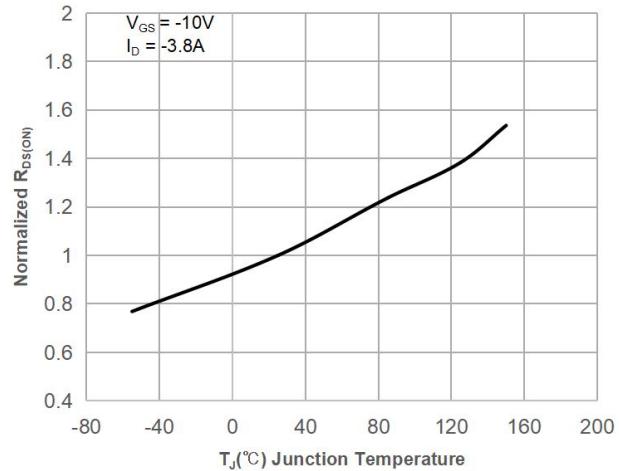


Figure 9: Maximum Safe Operating Area

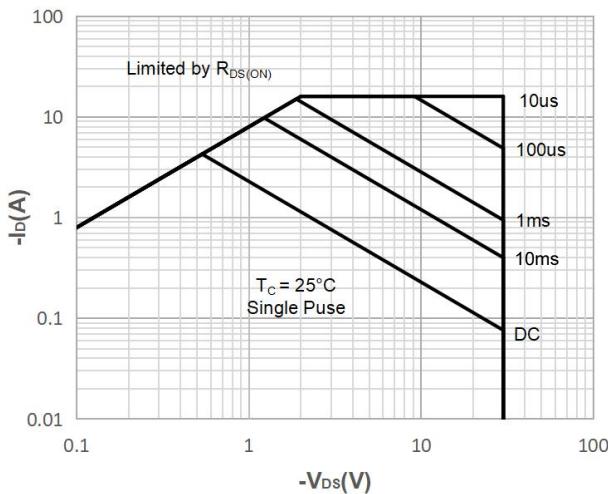


Figure 10: Maximum Continuous Drain Current vs. Case Temperature

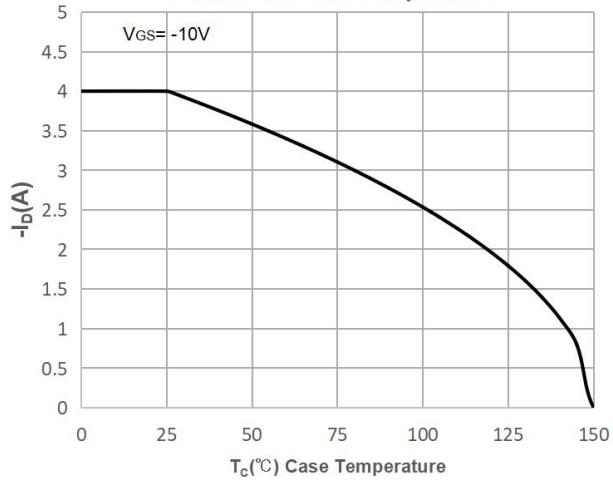


Figure 11: Normalized Maximum Transient Thermal Impedance

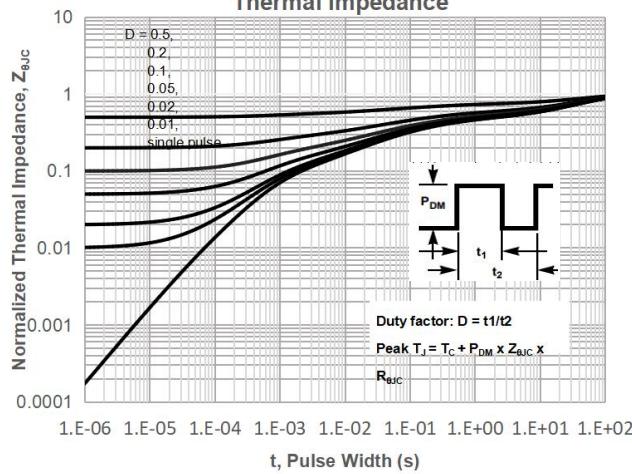
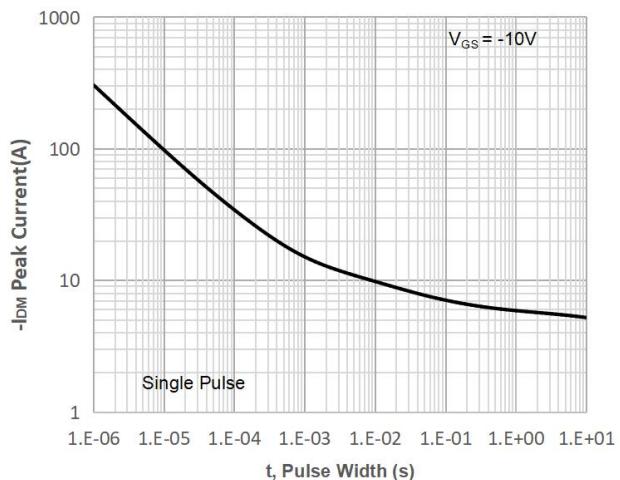


Figure 12: Peak Current Capacity



Test Circuit

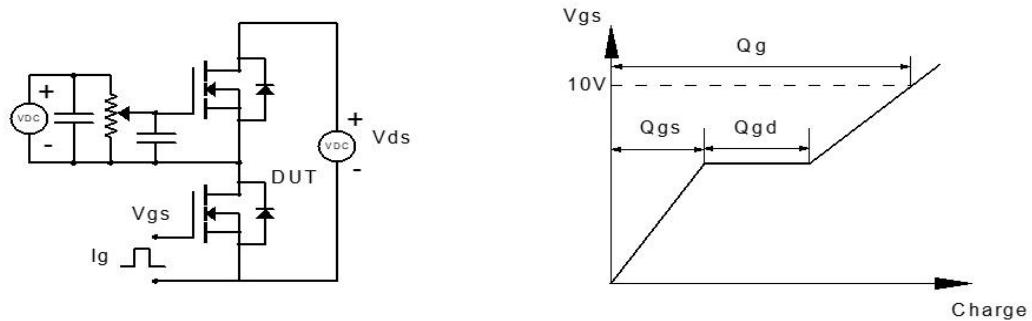


Figure 1: Gate Charge Test Circuit & Waveform

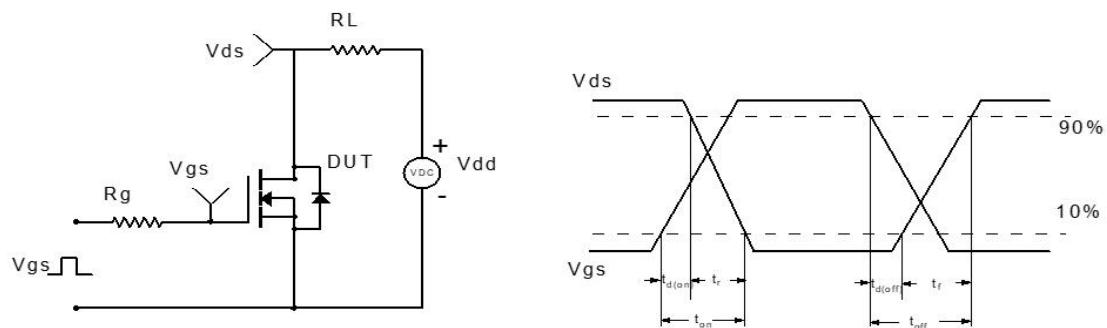


Figure 2: Resistive Switching Test Circuit & Waveform

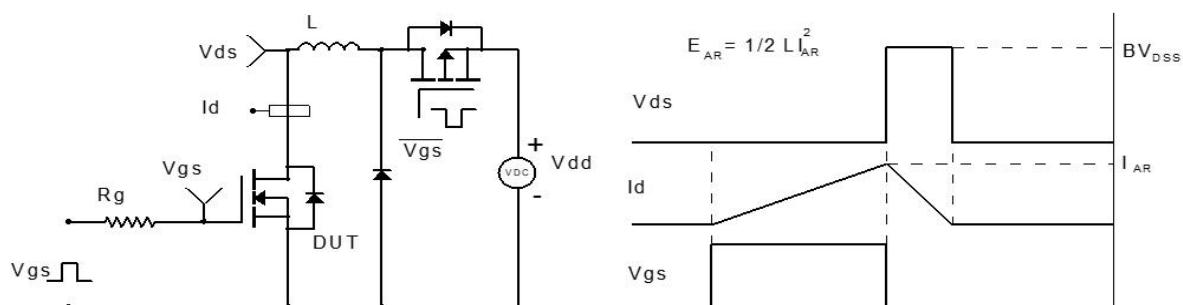


Figure 3: Unclamped Inductive Switching Test Circuit & Waveform

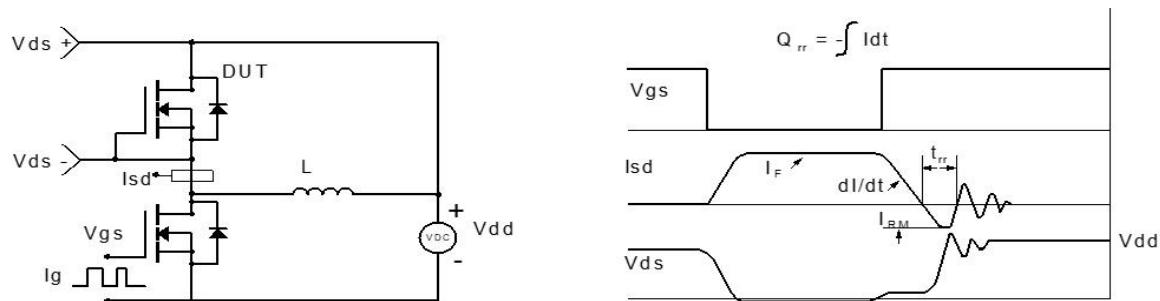
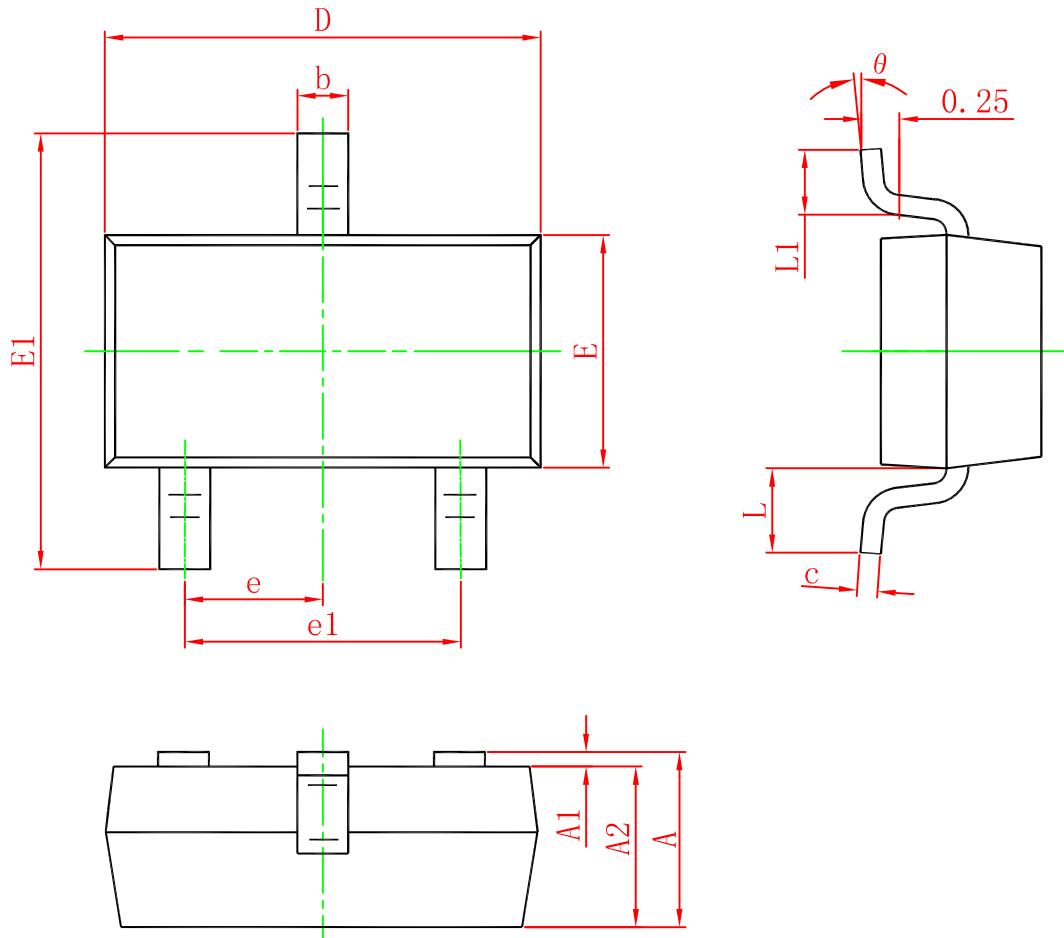


Figure 4: Diode Recovery Test Circuit & Waveform

SOT-23 Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
c	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
E	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
e	0.950 TYP.		0.037 TYP.	
e1	1.800	2.000	0.071	0.079
L	0.550 REF.		0.022 REF.	
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°